

<b>Notice of References Cited</b>	Application/Control No. 10/758,817		Applicant(s)/Patent Under Reexamination MARKS, RICHARD L.	
	Examiner KENT WANG		Art Unit 2622	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,769,769	08-2004	Podoleanu et al.	351/221
*	B	US-6,473,516	10-2002	Kawaguchi et al.	382/100
*	C	US-7,061,507	06-2006	Tuomi et al.	345/611
*	D	US-2001/0017932	08-2001	Chang, Kenneth H.P.	382/100
*	E	US-6,411,392	06-2002	Bender et al.	358/1.14
*	F	US-5,870,100	02-1999	DeFreitas, Scott C.	345/441
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Gvili et al. "Depth Keying", SPIE Vol. 5006 (2003), 2003 SPIE-IS&T, pp 564-574			
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.